

Ultra Series[™] Crystal Oscillator Si545 Data Sheet

Ultra Low Jitter Any-Frequency XO (80 fs), 0.2 to 1500 MHz

The Si545 Ultra Series[™] oscillator utilizes Silicon Laboratories' advanced 4th generation DSPLL® technology to provide an ultra-low jitter. low phase noise clock at any output frequency. The device is factory-programmed to any frequency from 0.2 to 1500 MHz with <1 ppb resolution and maintains exceptionally low jitter for both integer and fractional frequencies across its operating range. The Si545 offers excellent reliability and frequency stability as well as guaranteed aging performance. On-chip power supply filtering provides industry-leading power supply noise rejection, simplifying the task of generating low jitter clocks in noisy systems that use switched-mode power supplies. Offered in industry-standard footprints, the Si545 has a dramatically simplified supply chain that enables Silicon Labs to ship custom frequency samples 1-2 weeks after receipt of order. Unlike a traditional XO, where a different crystal is required for each output frequency, the Si545 uses one simple crystal and a DSPLL IC-based approach to provide the desired output frequency. This process also guarantees 100% electrical testing of every device. The Si545 is factory-configurable for a wide variety of user specifications, including frequency, output format, and OE pin location/polarity. Specific configurations are factory-programmed at time of shipment, eliminating the long lead times associated with custom oscillators.







5 x 7mm and 3.2 x 5 mm 2.5 x 3.2 mm

OE/NC	1	6	VDD
NC/OE	2	5	CLK-
GND	3	4	CLK+
	(Top	View)	

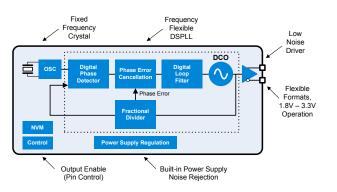
Pin #	Descriptions
1, 2	Selectable via ordering option OE = Output enable; NC = No connect
3	GND = Ground
4	CLK+ = Clock output
5	CLK- = Complementary clock output. Not used for CMOS.
6	VDD = Power supply

KEY FEATURES

- Available with any frequency from 0.2 MHz to 1500 MHz
- Ultra low jitter: 80 fs Typ RMS (12 kHz – 20 MHz)
- Excellent PSNR and supply noise immunity: –80 dBc Typ
- 7 ppm stability option (-40 to 85 °C)
- 3.3 V, 2.5 V and 1.8 V V_{DD} supply operation from the same part number
- LVPECL, LVDS, CML, HCSL, CMOS, and Dual CMOS output options
- 2.5×3.2, 3.2×5, 5×7 mm package options
- Samples available with 1-2 week lead times

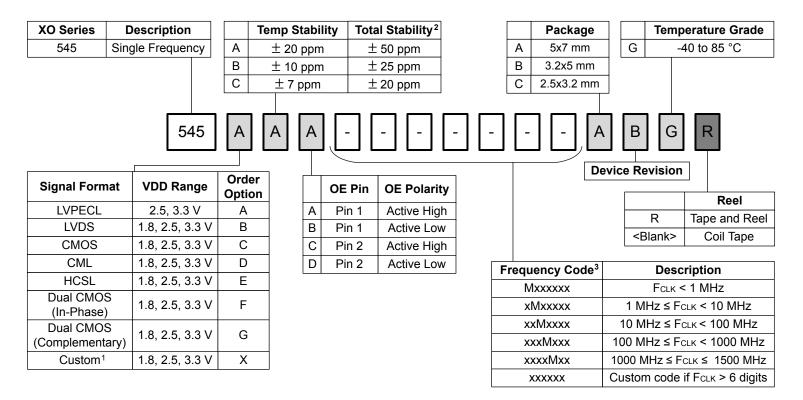
APPLICATIONS

- 100G/200G/400G OTN, coherent optics
- 10G/40G/100G optical ethernet
- 3G-SDI/12G-SDI/24G-SDI broadcast video
- Datacenter
- · Test and measurement
- · Clock and data recovery
- FPGA/ASIC clocking



1. Ordering Guide

The Si545 XO supports a variety of options including frequency, output format, and OE pin location/polarity, as shown in the chart below. Specific device configurations are programmed into the part at time of shipment, and samples are available in 1-2 weeks. Silicon Laboratories provides an online part number configuration utility to simplify this process. Refer to www.silabs.com/oscillators to access this tool and for further ordering instructions.



Notes:

- 1. Contact Silicon Labs for non-standard configurations.
- 2. Total stability includes temp stability, initial accuracy, load pulling, VDD variation, and 20 year aging at 70 °C.
- 3. For example: 156.25 MHz = 156M250; 25 MHz = 25M0000. Create custom part numbers at www.silabs.com/oscillators.

1.1 Technical Support

Frequently Asked Questions (FAQ)	www.silabs.com/Si545-FAQ
Oscillator Phase Noise Lookup Utility	www.silabs.com/oscillator-phase-noise-lookup
Quality and Reliability	www.silabs.com/quality
Development Kits	www.silabs.com/oscillator-tools

2. Electrical Specifications

Table 2.1. Electrical Specifications

 V_{DD} = 1.8 V, 2.5 or 3.3 V \pm 5%, T_A = –40 to 85 °C

Parameter	Symbol	Test Condition/Comment	Min	Тур	Max	Unit
Temperature Range	T _A		-40	_	85	°C
Frequency Range	F _{CLK}	LVPECL, LVDS, CML	0.2		1500	MHz
		HCSL	0.2		400	MHz
		CMOS, Dual CMOS	0.2	_	250	MHz
Supply Voltage	V _{DD}	3.3 V	3.135	3.3	3.465	V
		2.5 V	2.375	2.5	2.625	V
		1.8 V	1.71	1.8	1.89	V
Supply Current	I _{DD}	LVPECL (output enabled)	_	107	153	mA
		LVDS/CML (output enabled)	_	83	121	mA
		HCSL (output enabled)	_	86	126	mA
		CMOS (output enabled)	_	87	127	mA
		Dual CMOS (output enabled)	_	92	141	mA
		Tristate Hi-Z (output disabled)	—	73	112	mA
Temperature Stability		Frequency stability Grade A	-20	_	20	ppm
		Frequency stability Grade B	-10	_	10	ppm
		Frequency stability Grade C	-7	—	7	ppm
Total Stability ¹	F _{STAB}	Frequency stability Grade A	-50	—	50	ppm
		Frequency stability Grade B	-25		25	ppm
		Frequency stability Grade C	-20	_	20	ppm
Rise/Fall Time	T _R /T _F	LVPECL/LVDS/CML	_	_	350	ps
(20% to 80% V _{PP})		CMOS / Dual CMOS, (C _L = 5 pF)	_	0.5	1.5	ns
		HCSL, F _{CLK} >50 MHz	_	_	550	ps
Duty Cycle	D _C	All formats	45		55	%
Output Enable (OE) ²	V _{IH}		0.7 × V _{DD}	_		V
	V _{IL}		_	_	0.3 × V _{DD}	V
	T _D	Output Disable Time, F _{CLK} > 10 MHz	_	_	3	μs
	TE	Output Enable Time, F _{CLK} > 10 MHz	_		20	μs
Powerup Time	tosc	Time from 0.9 × V_{DD} until output frequency (F _{CLK}) within spec	-		10	ms
Powerup VDD Ramp Rate	V _{RAMP}	Fastest VDD ramp rate allowed on startup	-		9	V/ms
LVPECL Output Option ³	V _{OC}	Mid-level	V _{DD} – 1.42	—	V _{DD} – 1.25	V
	Vo	Swing (diff)	1.1	_	1.9	V _{PP}

Parameter	Symbol	Test Condition/Comment	Min	Тур	Max	Unit
LVDS Output Option ⁴	S Output Option ⁴ V _{OC} Mid-I		1.125	1.20	1.275	V
		Mid-level (1.8 V VDD)		0.9	1.0	V
	V _O Swing (F _{CL}		0.6	0.7	0.9	V _{PP}
		Swing (F _{CLK} > 1.4 GHz)	0.5	0.7	0.9	V _{PP}
HCSL Output Option ⁵	V _{OH}	Output voltage high	660	750	850	mV
	V _{OL}	Output voltage low	-150	0	150	mV
	V _C	Crossing voltage	250	350	550	mV
CML Output Option (AC-Coupled)	Vo	Swing (diff)	0.6	0.8	1.0	V_{PP}
CMOS Output Option	V _{OH}	I _{OH} = 8/6/4 mA for 3.3/2.5/1.8 V VDD	$0.85 \times V_{DD}$	—	—	V
	V _{OL}	I _{OL} = 8/6/4 mA for 3.3/2.5/1.8 V VDD	—	—	0.15 × V _{DD}	V

Notes:

1. Total Stability includes temperature stability, initial accuracy, load pulling, VDD variation, and aging for 20 yrs at 70 °C.

2. OE includes a 50 k Ω pull-up to VDD for OE active high. Includes a 50 k Ω pull-down to GND for OE active low.

3.50 Ω to V_DD – 2.0 V.

4. R_{term} = 100 Ω (differential).

5.50 Ω to GND.

Table 2.2. Clock Output Phase Jitter and PSNR

 V_{DD} = 1.8 V, 2.5 or 3.3 V \pm 5%, T_A = –40 to 85 °C

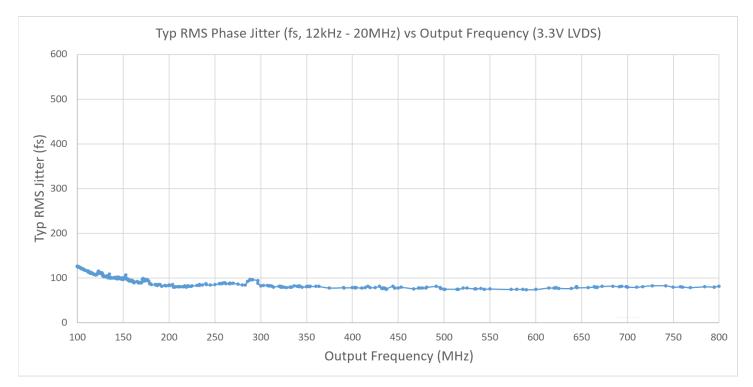
Parameter	Symbol	Test Condition/Comment	Min	Тур	Max	Unit	
Phase Jitter (RMS, 12kHz - 20MHz) ¹	фJ	F _{CLK} ≥ 200 MHz	_	80	110	fs	
3.2 x 5 mm, All Differential Formats		100 MHz ≤ F _{CLK} < 200 MHz		100	150	fs	
		LVPECL @ 156.25 MHz	_	90	125	fs	
Phase Jitter (RMS, 12kHz - 20MHz) ¹	фј	F _{CLK} ≥ 200 MHz	_	80	130	fs	
5 x 7 mm, All Differential Formats		100 MHz ≤ F _{CLK} < 200 MHz		100	150	fs	
		LVPECL @ 156.25 MHz	_	90	125	fs	
Phase Jitter (RMS, 12kHz - 20MHz) ¹	фј	F _{CLK} ≥ 200 MHz	_	90	130	fs	
2.5 x 3.2 mm, All Differential Formats		LVDS @ 625 MHz	_	90	130	fs	
		100 MHz ≤ F _{CLK} < 200 MHz	_	100	150	fs	
Phase Jitter (RMS, 12kHz - 20MHz) ¹ CMOS / Dual CMOS Formats	фJ	10 MHz ≤ F _{CLK} ≤ 250 MHz	_	200	_	fs	
Spurs Induced by External Power Supply	PSNR	100 kHz sine wave	_	-83	_		
Noise, 50 mVpp Ripple. LVDS 156.25 MHz Output		200 kHz sine wave	_	-83		dDa	
		500 kHz sine wave	_	-82		dBc	
		1 MHz sine wave	_	-85	_		

Note:

1. Guaranteed by characterization. Jitter inclusive of any spurs.

Offset Frequency (f)	156.25 MHz LVDS	200 MHz LVDS	644.53125 MHz LVDS	Unit
100 Hz	-106	-102	-92	
1 kHz	–133	–129	-119	
10 kHz	-140	–138	–127	
100 kHz	-145	-142	-132	dBc/Hz
1 MHz	-152	-150	-139	
10 MHz	–160	-160	-154	
20 MHz	–161	–161	-155	
Offset Frequency (f)	156.25 MHz LVPECL	200 MHz LVPECL	644.53125 MHz LVPECL	Unit
100 Hz	-103	-104	-91	
1 kHz	–130	–128	-118	
10 kHz	-140	–138	–127	
100 kHz	-145	-142	-132	dBc/Hz
1 MHz	–152	–150	-140	
10 MHz	-162	-162	-155	
20 MHz	-163	-163	-156	





Phase jitter measured with Agilent E5052 using a differential-to-single ended converter (balun or buffer). Measurements collected for >700 commonly used frequencies. Phase noise plots for specific frequencies are available using our free, online Oscillator Phase Noise Lookup Tool at www.silabs.com/oscillators.



Parameter	Test Condition
Mechanical Shock	MIL-STD-883, Method 2002
Mechanical Vibration	MIL-STD-883, Method 2007
Solderability	MIL-STD-883, Method 2003
Gross and Fine Leak	MIL-STD-883, Method 1014
Resistance to Solder Heat	MIL-STD-883, Method 2036
Moisture Sensitivity Level (MSL): 3.2 x 5, 5 x 7 packages	1
Moisture Sensitivity Level (MSL): 2.5 x 3.2 package	2
Contact Pads: 3.2x5, 5x7 packages	Au/Ni (0.3 - 1.0 μm / 1.27 - 8.89 μm)
Contact Pads: 2.5x3.2 packages	Au/Pd/Ni (0.03 - 0.12 μm / 0.1 - 0.2 μm / 3.0 - 8.0 μm)

Table 2.4. Environmental Compliance and Package Information

Note:

1. For additional product information not listed in the data sheet (e.g. RoHS Certifications, MDDS data, qualification data, REACH Declarations, ECCN codes, etc.), refer to our "Corporate Request For Information" portal found here: www.silabs.com/support/ quality/Pages/RoHSInformation.aspx.

Table 2.5. Thermal Conditions

Max Junction Temperature = 125° C

Package	Parameter	Symbol	Test Condition	Value	Unit
	Thermal Resistance Junction to Ambient	Θ _{JA}	Still Air, 85 °C	80	°C/W
2.5 x 3.2 mm 6-pin DFN	Thermal Parameter Junction to Board	Ψ_{JB}	Still Air, 85 °C	39	°C/W
•	Thermal Parameter Junction to Top Center	Ψ_{JT}	Still Air, 85 °C	17	°C/W
	Thermal Resistance Junction to Ambient	Θ _{JA}	Still Air, 85 °C	55	°C/W
3.2 × 5 mm 6-pin CLCC	Thermal Parameter Junction to Board	Ψ_{JB}	Still Air, 85 °C	20	°C/W
	Thermal Parameter Junction to Top Center	Ψ_{JT}	Still Air, 85 °C	20	°C/W
	Thermal Resistance Junction to Ambient	Θ _{JA}	Still Air, 85 °C	53	°C/W
5 × 7 mm 6-pin CLCC	Thermal Parameter Junction to Board	Ψ_{JB}	Still Air, 85 °C	26	°C/W
·	Thermal Parameter Junction to Top Center	Ψ_{JT}	Still Air, 85 °C	26	°C/W

Note:

1. Based on PCB Dimensions: 4.5" x 7", PCB Thickness: 1.6 mm, Number of Cu Layers: 4.

Table 2.6. Absolute Maximum Ratings¹

Parameter	Symbol	Rating	Unit
Maximum Operating Temp.	T _{AMAX}	95	°C
Storage Temperature	T _S	–55 to 125	°C
Supply Voltage	V _{DD}	-0.5 to 3.8	°C
Input Voltage	V _{IN}	–0.5 to V _{DD} + 0.3	V

Parameter	Symbol	Rating	Unit
ESD HBM (JESD22-A114)	HBM	2.0	kV
Solder Temperature ²	T _{PEAK}	260	°C
Solder Time at T _{PEAK} ²	Τ _Ρ	20–40	sec

Notes:

1. Stresses beyond those listed in this table may cause permanent damage to the device. Functional operation specification compliance is not implied at these conditions. Exposure to maximum rating conditions for extended periods may affect device reliability.

2. The device is compliant with JEDEC J-STD-020.

3. Dual CMOS Buffer

Dual CMOS output format ordering options support either complementary or in-phase signals for two identical frequency outputs. This feature enables replacement of multiple XOs with a single Si545 device.

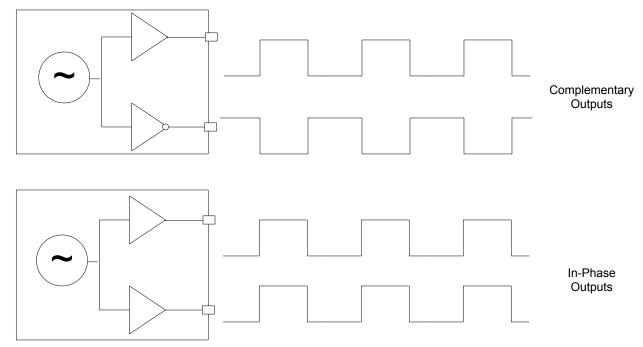


Figure 3.1. Integrated 1:2 CMOS Buffer Supports Complementary or In-Phase Outputs

4. Recommended Output Terminations

The output drivers support both AC-coupled and DC-coupled terminations as shown in figures below.

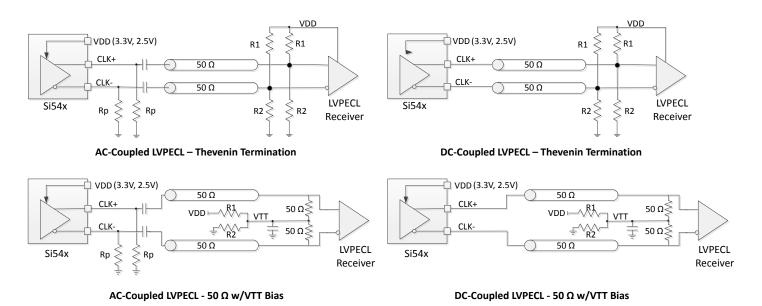
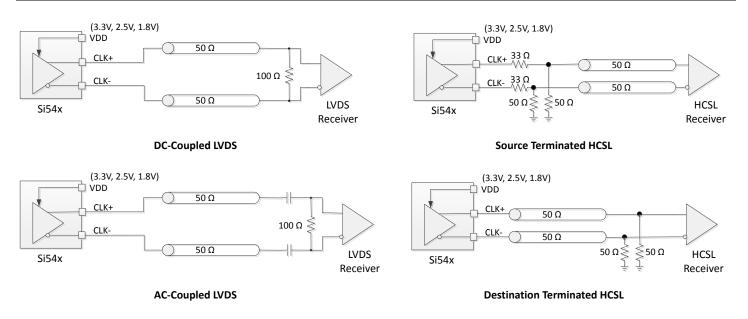


Figure 4.1. LVPECL Output Terminations

AC Coupled LVPECL Termination Resistor Values					DC Coupled LVPECL mination Resistor Va	
VDD	R1	R2	Rp	VDD	R1	R2
3.3 V	127 Ω	82.5 Ω	130 Ω	3.3 V	127 Ω	82.5 Ω
2.5 V	250 Ω	62.5 Ω	90 Ω	2.5 V	250 Ω	62.5 Ω





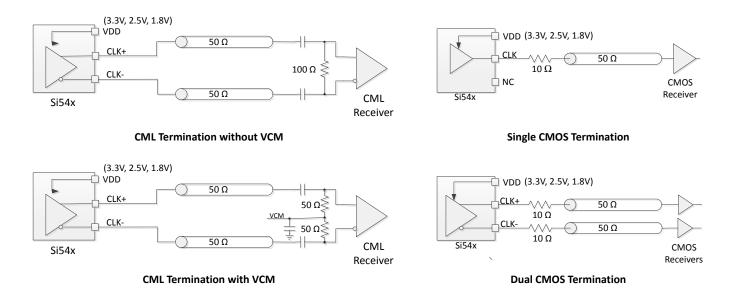
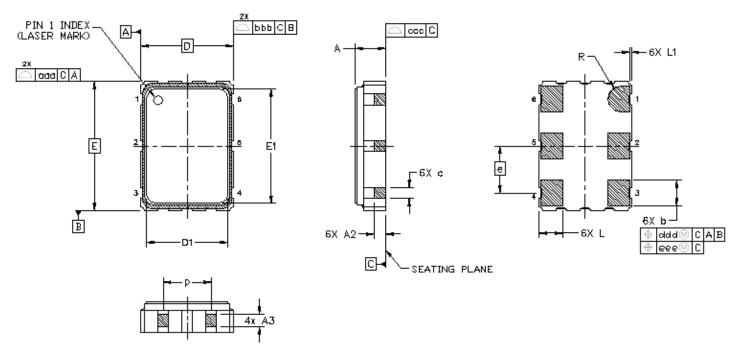


Figure 4.3. CML and CMOS Output Terminations

5. Package Outline

5.1 Package Outline (5×7 mm)

The figure below illustrates the package details for the 5×7 mm Si545. The table below lists the values for the dimensions shown in the illustration.



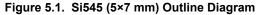


Table 5.1.	Package	Diagram	Dimensions	(mm)
------------	---------	---------	------------	------

Dimension	Min	Nom	Max	Dimension	Min	Nom	Max
А	1.13	1.28	1.43	L	1.17	1.27	1.37
A2	0.50	0.55	0.60	L1	0.05	0.10	0.15
A3	0.50	0.55	0.60	р	1.70	_	1.90
b	1.30	1.40	1.50	R		0.70 REF	
С	0.50	0.60	0.70	ааа	0.15		
D	5.00 BSC			bbb		0.15	
D1	4.30 4.40 4.50			CCC		0.08	
е	2.54 BSC			ddd		0.10	
E	7.00 BSC			eee		0.05	
E1	6.10	6.20	6.30				

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.

2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

5.2 Package Outline (3.2×5 mm)

The figure below illustrates the package details for the 3.2×5 mm Si545. The table below lists the values for the dimensions shown in the illustration.

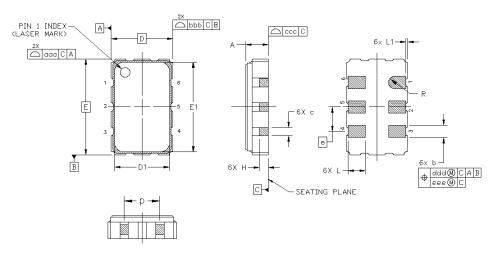


Figure 5.2. Si545 (3.2×5 mm) Outline Diagram

Dimension	Min	Nom	Max	
A	1.06	1.17	1.33	
b	0.54	0.64	0.74	
C	0.35	0.45	0.55	
D		3.20 BSC		
D1	2.55	2.60	2.65	
е	1.27 BSC			
E	5.00 BSC			
E1	4.35	4.40	4.45	
Н	0.45	0.55	0.65	
L	0.80	0.90	1.00	
L1	0.05	0.10	0.15	
р	1.36	1.46	1.56	
R		0.32 REF		
ааа		0.15		
bbb	0.15			
CCC	0.08			
ddd		0.10		
eee		0.05		

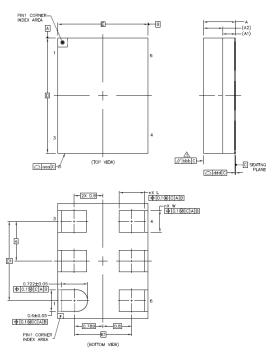
Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.

2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

5.3 Package Outline (2.5x3.2 mm)

The figure below illustrates the package details for the 2.5x3.2 mm Si545. The table below lists the values for the dimensions shown in the illustration.



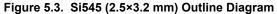


Table 5.3. Package Diagram Dimensions ((mm)	1
---	------	---

Min	Nom	Мах	
0.90	0.95	1.00	
0.36 REF			
	0.53 REF		
0.55	0.60	0.65	
3.2 BSC			
2.5 BSC			
1.10 BSC			
0.65 0.70 0.75			
5			
2.2 BSC			
1.589 BSC			
0.10			
0.10			
	0.08		
	0.90	0.90 0.95 0.36 REF 0.53 REF 0.55 0.60 3.2 BSC 2.5 BSC 1.10 BSC 0.65 0.70 5 2.2 BSC 1.589 BSC 0.10	

Notes:

1. The dimensions in parentheses are reference.

2. All dimensions in millimeters (mm).

3. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

6. PCB Land Pattern

6.1 PCB Land Pattern (5×7 mm)

The figure below illustrates the 5×7 mm PCB land pattern for the Si545. The table below lists the values for the dimensions shown in the illustration.

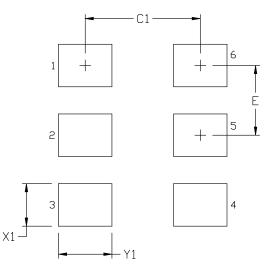


Figure 6.1. Si545 (5×7 mm) PCB Land Pattern

Table 6.1.	PCB Land	Pattern	Dimensions	(mm)
------------	----------	---------	------------	------

Dimension	(mm)
C1	4.20
E	2.54
X1	1.55
Y1	1.95

Notes:

General

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
- 3. This Land Pattern Design is based on the IPC-7351 guidelines.
- 4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

Solder Mask Design

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

Stencil Design

- 1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
- 2. The stencil thickness should be 0.125 mm (5 mils).
- 3. The ratio of stencil aperture to land pad size should be 1:1.

Card Assembly

- 1. A No-Clean, Type-3 solder paste is recommended.
- 2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

6.2 PCB Land Pattern (3.2×5 mm)

The figure below illustrates the 3.2×5.0 mm PCB land pattern for the Si545. The table below lists the values for the dimensions shown in the illustration.

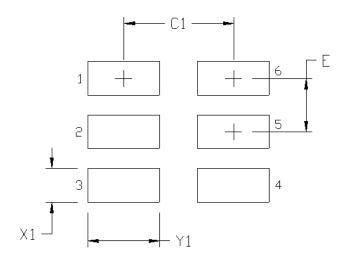


Figure 6.2. Si545 (3.2×5 mm) PCB Land Pattern

Table 6.2. PCB Land Pattern Dimensions (mm)

Dimension	(mm)
C1	2.60
E	1.27
X1	0.80
Y1	1.70

Notes:

General

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
- 3. This Land Pattern Design is based on the IPC-7351 guidelines.
- 4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

Solder Mask Design

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

Stencil Design

- 1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
- 2. The stencil thickness should be 0.125 mm (5 mils).
- 3. The ratio of stencil aperture to land pad size should be 1:1.

Card Assembly

- 1. A No-Clean, Type-3 solder paste is recommended.
- 2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

6.3 PCB Land Pattern (2.5×3.2 mm)

The figure below illustrates the 2.5×3.2 mm PCB land pattern for the Si545. The table below lists the values for the dimensions shown in the illustration.

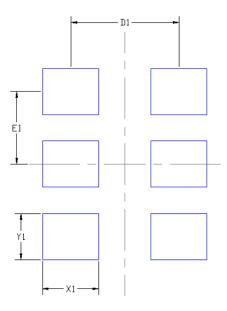


Figure 6.3. Si545 (2.5×3.2 mm) PCB Land Pattern

Table 6.3. PCB Land Pattern Dimensions (mm)

Dimension	Description Value (mm)		
X1	Width - leads on long sides	0.85	
Y1	Height - leads on long sides	0.7	
D1	Pitch in X directions of XLY1 leads	1.639	
E1	Lead pitch XLY1 leads 1.10		

Notes: The following notes and stencil design are shared as recommendations only. A customer or user may find it necessary to use different parameters and fine-tune their SMT process as required for their application and tooling.

General

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
- 3. This Land Pattern Design is based on the IPC-7351 guidelines.
- 4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

Solder Mask Design

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

Stencil Design

- 1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
- 2. The stencil thickness should be 0.125 mm (5 mils).
- 3. The ratio of stencil aperture to land pad size should be 0.8:1 for the pads.

Card Assembly

- 1. A No-Clean, Type-3 solder paste is recommended.
- 2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

7. Top Marking (5x7 and 3.2x5 Packages)

The figure below illustrates the mark specification for the Si545 5x7 and 3.2x5 package sizes. The table below lists the line information.

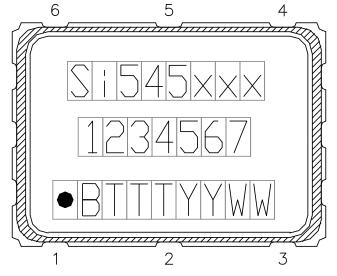


Figure 7.1. Mark Specification

Table 7.1.	Si545	Тор	Mark	Description
------------	-------	-----	------	-------------

Line	Position	Description	
1	1–8	"Si545", xxx = Ordering Option 1, Option 2, Option 3 (e.g. Si545AAA)	
2	1–7	Frequency Code (e.g. 100M000 or 6-digit custom code as described in the Ordering Guide)	
3	Trace Code		
	Position 1	Position 1 Pin 1 orientation mark (dot)	
	Position 2	Position 2 Product Revision (B)	
	Position 3–5	Tiny Trace Code (3 alphanumeric characters per assembly release instructions)	
	Position 6–7	Year (last two digits of the year), to be assigned by assembly site (ex: 2017 = 17)	
	Position 8–9	Calendar Work Week number (1–53), to be assigned by assembly site	

8. Top Marking (2.5x3.2 Package)

The figure below illustrates the mark specification for the Si545 2.5x3.2 package sizes. The table below lists the line information.

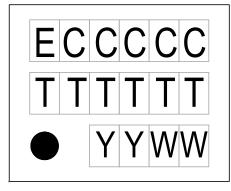


Figure 8.1. Mark Specification

Table 8.1. Si545 Top Mark Description

Line	Position	Description
1	1–6	E = Si545, CCCCC = Custom Mark Code
2	Trace Code	
	1–6	Six-digit trace code per assembly release instructions
3	Position 1	Pin 1 orientation mark (dot)
	Position 2–3	Year (last two digits of the year), to be assigned by assembly site (exp: 2017 = 17)
	Position 4–5	Calendar Work Week number (1–53), to be assigned by assembly site

9. Revision History

Revision 1.2

September 2020

Updated Table 2.2, Powerup VDD Ramp Rate and LVDS Swing

Revision 1.1

December 2019

• Added 2.5x3.2 mm package and land drawing.

Revision 1.0

July 2018

Added 20 ppm total stability option.

Revision 0.75

March 2018

• Added 25 ppm total stability option.

Revision 0.71

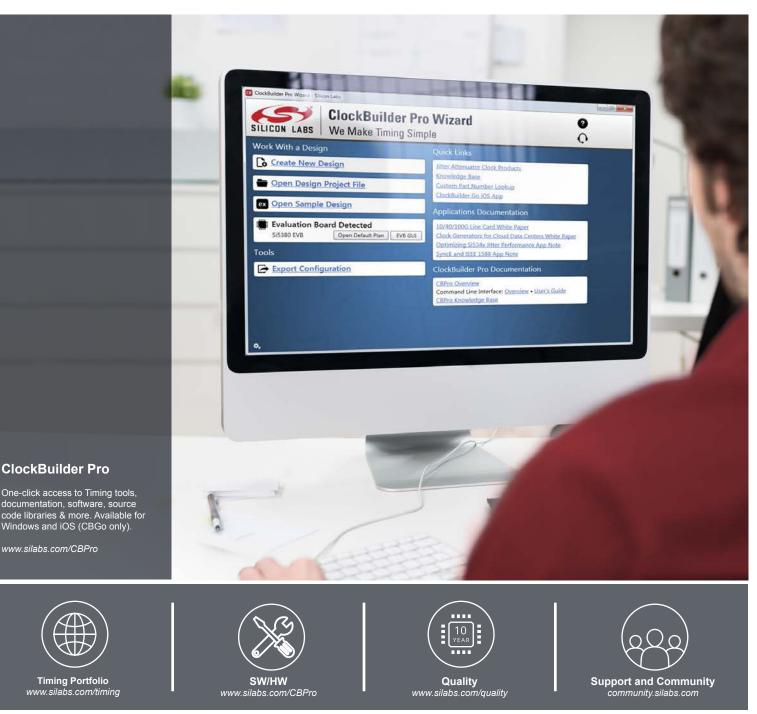
December 11, 2017

Added 5x7 package and land pattern.

Revision 0.7

June 27, 2017

· Initial release.



Disclaimer

Silicon Labs intends to provide customers with the latest, accurate, and in-depth documentation of all peripherals and modules available for system and software implementers using or intending to use the Silicon Labs products. Characterization data, available modules and peripherals, memory sizes and memory addresses refer to each specific device, and "Typical" parameters provided can and do vary in different applications. Application examples described herein are for illustrative purposes only. Silicon Labs reserves the right to make changes without further notice to the product information, specifications, and descriptions herein, and does not give warranties as to the accuracy or completeness of the included information. Without prior notification, Silicon Labs shall have no liability for the consequences of use of the information supplied in this document. This document does not imply or expressly grant any license to design or fabricate any integrated circuits. The products are not designed or authorized to be used within any FDA Class III devices, applications for which FDA premarket approval is required, or Life Support Systems without the specific written consent of Silicon Labs. A "Life Support System" is any product or system intended to support or sustain life and/or health, which, if it fails, can be reasonably expected to result in significant personal injury or death. Silicon Labs products are not designed or authorized for military applications. Silicon Labs product shall under no circumstances be used in weapons of mass destruction including (but not limited to) nuclear, biological or chemical weapons, or missiles capable of delivering such weapons. Silicon Labs disclaims all express and implied warranties and shall not be responsible or liable for any injuries or damages related to use of a Silicon Labs product in such unauthorized applications.

Trademark Information

Silicon Laboratories Inc.®, Silicon Laboratories®, Silicon Labs®, SiLabs® and the Silicon Labs logo®, Bluegiga®, Bluegiga Logo®, ClockBuilder®, CMEMS®, DSPLL®, EFM®, EFM32®, EFR, Ember®, Energy Micro, Energy Micro logo and combinations thereof, "the world's most energy friendly microcontrollers", Ember®, EZLink®, EZRadio®, EZRadio®, Gecko®, Gecko OS, Gecko OS, Studio, ISOmodem®, Precision32®, ProSLIC®, Simplicity Studio®, SiPHY®, Telegesis, the Telegesis Logo®, USBXpress®, Zentri, the Zentri logo and Zentri DMS, Z-Wave®, and others are trademarks or registered trademarks of Silicon Labs. ARM, CORTEX, Cortex-M3 and THUMB are trademarks or registered trademarks of ARM Holdings. Keil is a registered trademark of the Wi-Fi Alliance. All other products or brand names mentioned herein are trademarks of their respective holders.



Silicon Laboratories Inc. 400 West Cesar Chavez Austin, TX 78701 USA

http://www.silabs.com